Supporting Information for

A Facile Route to Synthesis Silica Shell Free Silicide Nanowires

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Syntheses and characterizations of GdSi₂ NWs

GdSi₂ nanostructures were synthesized between 800 °C and 850 °C with the similar setup for ErSi₂ NWs as described in the experimental section. The reaction temperature strongly affects the GdSi₂ nanostructure morphologies. At low reaction temperature (800 °C), high aspect ratio, vicinal GdSi₂ NWs (~10 nm width and several micron length) grew on the Si (001) surface (Figure S4a). An increase in the reaction temperature to 820 °C induced the formation of low aspect ratio, vicinal GdSi₂ nanorods (~80 nm widths and 1 micron length) (Figure S4b). If the reaction temperature was even higher at 850 °C, due to the high deposition rate of gadolinium, large particles covered the silicon surface and inhibited the growth of contacted silicide nanostructures (Figure S4c).

Free-standing GdSi₂ NWs were obtained by lengthening the reaction time. These free-standing NWs were then collected by scratching the silicon substrate surface and dispersing them into IPA solution for TEM characterizations.



Figure S1. Phase diagram of system Na₂O-SiO₂.



Figure S2. FESEM image of $ErSi_2$ NWs grew on Si(001) surface at 820°C for 1.5 h. The twinned NWs are circled.



Figure S3. Energy dispersive spectra of ErSi₂ NWs. No impurities were detected.



Figure S4. FESEM images of the $GdSi_2$ NWs grew on Si (001) surface at different temperature and reaction time. The synthesis was carried out at (a) 800 °C for 1 h, (b) 820 °C for 1 h, and (c) 850 °C, 1 h. Micron sized particles covered the silicon surface. (d) $GdSi_2$ NW sample was grown on Si (001) at 820 °C for 5h.



Figure S5. XRD pattern of the $ErSi_2$ nanostructures grown on Si (111) wafer.